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|--|----|-----------------------------------|---------------------|----------------------|------------------------|---------------------------------------|----------------------------------|----|-------------|--|
| APPLICANTS | | | | | | | | | | |
| Shun-ichi Fukuyama, Kawasaki, JAPAN, | | | | | | | | | | |
| Tamotsu Owada, Kawasaki, JAPAN; Hiroko Inoue, Kawasaki, JAPAN;Ken Sugimoto, Kawasaki, JAPAN; | | | | | | | | | | |
| CONTINUING DATA | | | | | | | | | | |
| ** FOREIGN APPLICATIONS ************************************ | | | | | | | | | | |
| IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 10/28/2003 | | | | | | | | | | |
| Foreign Priority claimed yes no no 35 USC 119 (a-d) conditions Naves no Met after | | | | STATE OR | SHEETS | | тот | AL | INDEPENDENT | |
| 35 USC 119 (a-d) conditions wes no Met after Met after Allovand Acknowledged Examiner's Signature Initials | | | | COUNTRY JAPAN | DRAWING 4 | | CLAII | | CLAIMS 3 | |
| ADDRESS 38834 WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP 1250 CONNECTICUT AVENUE, NW SUITE 700 WASHINGTON, DC 20036 Semiconductor, device using low-k material as interlayer insulating TITLE film and including a surface modifying layer Semiconductor device using low-k material as interlayer insulating | | | | | | | | | | |
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| | | | | T ACCOUNT | | 1.16 Fees (Filing) | | | | |
| } · • | ۷o | : Authority has been gi | aper POSIT ACCOU | | | 1.17 Fees (Processing Ext. of time) | | | | |
| RECEIVED 1150 | ۱o | o for following: | | | | 1.18 Fees (Issue) | | | | |
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